

# Dual Precision JFET-Input Operational Amplifier

OP-215

### **FEATURES**

•	High Siew Rate	10V/μs Min
	Fast Settling Time 0.9 µs	
•	Low Input Offset Voltage Drift	I0μV/°C Max
•	Wide Bandwidth	3.5MHz Min
	_	

- Temperature-Compensated Input Bias Currents
- Guaranteed Input Blas Current .... 18nA Max (125°C)
- Blas Current Specified Warmed-Up Over Temperature
- Low Input Noise Current ...... 0.01pA/√Hz Typ
- High Common-Mode Rejection Ratio . . . . . . 86dB Min
- Pin Compatible With Standard Dual Pinouts
- 125°C Temperature Tested DICE
- Models With MIL-STD-883 Class B Processing Available
- Available in Die Form

## ORDERING INFORMATION 1

T_ = 25°C	<b>:</b>	PACKAGE									
V <sub>oe</sub> MAX (mV)	TO-99	CERDIP 8-PIN	PLASTIC 8-PIN	LCC 20-CONTACT	TEMPERATURE RANGE						
1.0 C	P215AJ*	OP215AZ*	-	_	MIL						
1.0 C	P215EJ	OP215EZ	OP215EP	-	СОМ						
2.0 C	P215BJ/883	OP215BZ/883	- (	DP215BRC/88	3 MIL						
2.0 C	P215FJ	OP215FZ	OP215FP	_	COM						
4.0 C	P215CJ/883	OP215CZ/883	_	_	MIL						
6.0	_	OP215GZ	OP215GP	_	XIND						
6.0	-	-	OP215GS	_	XIND						

- For devices processed in total compliance to MIL-STD-883, add /883 after part number. Consult factory for 883 data sheet.
- † Burn-in is available on commercial and industrial temperature range parts in CerDIP, plastic DIP, and TO-can packages.

### **GENERAL DESCRIPTION**

The OP-215 offers the proven JFET-input performance advantages of high speed and low input bias current with the

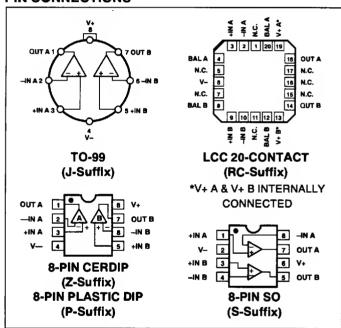
tracking and convenience advantages of a dual op-amp configuration.

Low input offset voltages, low input currents, and low drift are featured in these high-speed amplifiers.

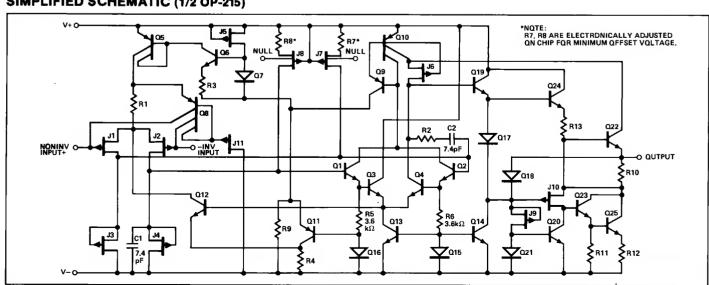
On-chip zener-zap trimming is used to achieve low  $V_{OS}$  while a bias-current compensation scheme gives a low input bias current at elevated temperatures. Thus the OP-215 features an input bias current of 18nA at 125°C ambient (not junction) temperature which greatly extends the application usefulness of this device.

Applications include high-speed amplifiers for current output DACs, active filters, sample-and-hold buffers, and photocell

### **PIN CONNECTIONS**



# SIMPLIFIED SCHEMATIC (1/2 OP-215)



# **OP-215**

# **GENERAL DESCRIPTION** Continued

amplifiers. For additional precision JFET op amps, see the OP-15/16/17 data sheet.

# **ABSOLUTE MAXIMUM RATINGS (Note 1)**

	•
Supply Voltage	
OP-215A, OP-215B, OP-215E, OP-215F	
(All DICE Except GR)	±22V
OP-215C, OP-215G (GR DICE Only)	±18V
Operating Temperature Range	
OP-215A, OP-215B, OP-215C	-55°C to +125°C
OP-215E, OP215F	0°C to + 70°C
OP-215G	
Maximum Junction Temperature (T <sub>i</sub> )	
Differential Input Voltage	
OP-215A, OP-215B, (All DICE Except GR)	±40V
OP-215E, OP-215F, (All DICE Except GR)	±40V
OP-215C, OP-215G, (GR DICE Only)	
Input Voltage	
OP-215A, OP-215B, (All DICE Except GR)	±20V
OP-215E, OP-215F, (All DICE Except GR)	

OP-215C, OP-215G, (GR DICE Only)	±16V
(Unless otherwise specified, the absolute maximum	
tive input voltage is equal to one volt more positive the	ian the
negative power supply voltage.)	
Output Short-Circuit Duration	ndefinite

Output Short-Circuit Duration	Indefinite
Storage Temperature Range	
Lead Temperature (Soldering, 60 sec)	
Junction Temperature (T <sub>i</sub> )	
' 'I'	

PACKAGE TYPE	θ <sub>jA</sub> (NOTE 2)	e <sub>jc</sub>	UNITS
TO-99 (J)	145	16	°C/W
8-Pin Hermetic DIP (Z)	134	12	°C/W
8-Pin Plastic DIP (P)	96	37	•C/W
20-Contact LCC (RC)	88	33	°C/W
8-Pin SO (S)	150	41	°C/W

### NOTES:

- Absolute maximum ratings apply to both DICE and packaged parts, unless otherwise noted.
- e is specified for worst case mounting conditions, i.e., e is specified for device in socket for TO, CerDIP, P-DIP, and LCC packages; e is specified for device soldered to printed circuit board for SO package.

# **ELECTRICAL CHARACTERISTICS** at $V_S = \pm\,15V$ , $T_A = 25^{\circ}\,C$ , unless otherwise noted.

			0	P-215A	/E	O	P-215B	/F	O	P-215C	:/G	
PARAMETER	SYMBOL	YMBOL CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
		$R_S = 50\Omega$		0.2	1,0		0.8	2.0	_	2.0	4.0	
Input Offset Voltage	vos	'G' Grade	_	_	_	_	-			2.5	6.0	mV
		T <sub>i</sub> = 25° C (Note 1)		3	50	_	3	50	_	3	100	- 4
Input Offset Current	los	Device Operating	_	5	100	_	5	100		5	200	pA
input Blas Current		T <sub>i</sub> = 25° C (Note 1)		± 15	± 100	_	±15	±200	_	±15	±300	nA.
	Device Operating	,	_	±18	±300		±18	±400		± 18	±600	pA
Input Resistance	R <sub>IN</sub>			1012	_		10 <sup>12</sup>			10 <sup>12</sup>		Ω
Large-Signal Voltage		R <sub>L</sub> ≥ 2kΩ	450	500		75	220	_	50	200	_	V/mV
Gain	Avo	V <sub>O</sub> = ±10V	150	500						200		
Output Voltage		$R_1 = 10k\Omega$	± 12	± 13	_	±12	±13	_	±12	±13	_	v
Swing	v <sub>o</sub>	$R_L = 2k\Omega$	±11	±12.7		±11	±12.7		±11_	±12.7	_	
			_	6.0	8.5	_	8.0	8.5	_	7.0	10.0	mA
Supply Current	ISY	'G' Grade					_			7.0	12.0	
Slew Rate	SR	A <sub>VCL</sub> = +1	10	18		7.5	18		5	15		V/µs
Gain Bandwidth Product	GBW	(Note 3)	3.5	5.7		3.5	5.7	_	3.0	5.4	_	MHz
Closed-Loop Bandwidth	CLBW	A <sub>VCL</sub> = +1	_	13	<del>-</del>	_	13			12	_	MHz
		to 0.01%		2.3	_	_	2.3	_	_	2.4	_	
Settling Time	ts	to 0.05% (Note 2)	_	1.1	_	_	1.1	_	-	1.2	_	μs
		to 0.10%		0.9			0.9			1.0		
	0.45		+10.2	+ 14.8	_	+10.2	+14.8	_	+10.1	+14.8	_	v
Input Voltage Range	IVR		-10.2	-11.5		-10.2	-11.5		-10.1	-11.5		
Common-Mode		A, B, C Grades	86	100	_	86	100	_	82	96	_	dB
Rejection Ratio	CMRR	V <sub>CM</sub> = ± IVR E, F, G Grades	82	100		82	100		80	96		
Power Supply	0000	$V_{S} = \pm 10V \text{ to } \pm 16V$	_	10	51	_	10	80	_	_	_	ν/۷
Rejection Ratio	PSRR	$V_S = \pm 10V \text{ to } \pm 15V$								18	100	μΨ/Ψ
Input Noise Voltage	_	f <sub>O</sub> = 100Hz	_	20	_	_	20	_	_	20	-	nV/√Hz
Density	en	f <sub>O</sub> = 1000Hz		15			15			15		
Input Noise Current		f <sub>O</sub> = 100Hz	-	0.01	_	-	0.01	_	_	0.01	_	pA/√Hz
Density	l <sub>n</sub>	f <sub>O</sub> = 1000Hz		0.01			0.01	_		0.01		
Input Capacitance	CIN		_	3		<del>-</del>	3	_	_	3	_	pF

**ELECTRICAL CHARACTERISTICS** at  $V_S = \pm\,15V$ ,  $-55^{\circ}\,C \le T_A \le +\,125^{\circ}\,C$ , unless otherwise noted.

		î		)P-215	A		)P-215	В		)P-215	C	
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
Input Offset Voltage	vos	$R_S = 50\Omega$	_	0.5	2.0	_	1.5	3.0		3.0	8.0	mV
Average Input Offset Voltage Drift												
Without External Trim	TCVOS	(Note 3)	_	3	10	_	3	10	_	6	_	1410.00
With External Trim	TCVOSn	$R_p = 100k\Omega$		3	_	_	3	_	_	4	_	μV/°C
Input Offset Current		T <sub>i</sub> = +125°C	_	0.8	8		0.8	8		1.0	12	
(Note 1)	los	T <sub>A</sub> = + 125°C, Device Operating	, –	1.2	14	_	1.2	14	_	1.5	22	nA
Input Bias Current		T <sub>i</sub> = +125°C		±1.5	±10	_	±1.5	±10	_	±1.8	± 15	0
(Note 1)	I <sub>B</sub>	T <sub>A</sub> = +125°C, Device Operating	<b>,</b> –	±2.2	±18	_	±2.2	±18	_	±2.7	±28	nA
Input Valtage Renge	IVR	-	+ 10.2	+14.6	_	+10.2	+14.6	_	+10.1	+14.6	_	v
Input Voltage Range	IVH		-10.2	-11.3		-10.2	-11.3		-10.1	-11.3		v
Common-Mode Rejection Ratio	CMRR	V <sub>CM</sub> = ±IVR	82	97	-	82	97	-	80	93	_	dB
Power Supply		V <sub>S</sub> = ±10V to ±16V	_	10	100	_	15	100	_	_	_	
Rejection Ratio	PSRR	$V_S = \pm 10V \text{ to } \pm 15V$	_	_		_	_		_	23	126	μ <b>V</b> /V
Large-Signal Voltage Gain	A <sub>VO</sub>	$R_{L} \ge 2k\Omega$ $V_{O} = \pm 10V$	30	110	_	30	110	_	25	100	_	V/mV
Output Voltage Swing	<b>v</b> <sub>o</sub>	R <sub>L</sub> ≥ 10kΩ	±12	± 13	_	±12	±13	_	±12	±13	_	v

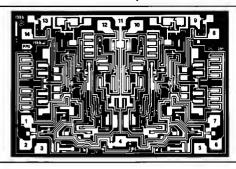
# **ELECTRICAL CHARACTERISTICS** at $V_S = \pm 15V$ , $0^{\circ}C \le T_A \le +70^{\circ}C$ for E/F Grades, $-40^{\circ}C \le T_A \le +85^{\circ}C$ for G Grade, unless otherwise noted.

			(	DP-215	E	(	DP-215	F		)P-215	G	
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
Input Offset Voltage	vos	R <sub>S</sub> = 50Ω		0.4	1.65	_	1.4	2.65	_	3.5	8.0	m۱
Average Input Offset Voltage Drift												
Without External Trim	TCVos	(Note 3)	_	3	15	_	3	15	_	6	_	V/0.0
With External Trim	TCV <sub>OSn</sub>	$R_{p} = 100k\Omega$	_	3			3	-	_	4	_	<b>μV</b> /° C
Input Offset Current		T <sub>i</sub> = +70°C		0.06	0.45	_	0.06	0.45	_	0.08	0.65	
(Note 1)	los	T <sub>A</sub> = +70°C, Device Operating	_	0.08	0.80	_	0.08	0.80	_	0.10	1.2	nA
Input Bias Current		T <sub>i</sub> = +70°C	_	±0.12	±0.70	_	±0.12	±0.70	_	±0.14	±0.9	4
(Note 1)	IB	T <sub>A</sub> = +70°C, Device Operating	_	±0.16	±1.40	_	±0.16	±1.40		±0.19	±1.8	nA
Inned Voltage Reads	IVR	•	+ 10.2	+14.7	_	+10.2	+14.7	_	+10.1	+14.7	_	v
Input Voltage Range	IVN		-10.2	-11.4		-10.2	-11.4	_	-10.1	-11.3	_	
Common-Mode Rejection Ratio	CMRR	V <sub>CM</sub> = ±IVR	80	98	-	80	98	-	76	94	_	₫B
Power Supply	2022	V <sub>S</sub> = ±10V to ±16V	_	13	100	_	13	100	_	_	_	1404
Rejection Ratio	PSRR	V <sub>S</sub> = ±10V to ±15V	_	_		_		_	_	20	159	μ <b>V</b> /V
Large-Signal Voltage Gain	Avo	$R_L \ge 2k\Omega$ $V_O = \pm 10V$	50	180	_	50	180	_	35	130	_	V/mV
Output Voltage Swing	v <sub>o</sub>	R <sub>L</sub> ≥ 10kΩ	±12	±13	_	±12	±13	_	±12	±13	_	٧

### NOTES:

- input bias current is specified for two different conditions. The T<sub>j</sub> = 25° C specification is with the junction at ambient temperature; the Device Operating specification is with the device operating in a warmed-up condition at 25° C ambient. The warmed-up bias current value is correlated to the junction temperature value via the curves of i<sub>B</sub> vs. T<sub>j</sub> and I<sub>B</sub> vs. T<sub>A</sub>. PMi has a bias current compensation circuit which gives improved bias current and bias current over temperature vs. standard JFET input op amps. i<sub>B</sub> and i<sub>OS</sub> are measured at V<sub>CM</sub> = 0.
- Settling time is defined here for a unity gain inverter connection using 2kΩ
  resistors. It is the time required for the error voltage (the voltage at the
  inverting input pin on the amplifier) to settle to within a specified percent of
  its final value from the time a 10V step input is applied to the inverter. See
  settling time test circuit.
- 3. Sample tested.

# DICE CHARACTERISTICS (125°C TESTED DICE AVAILABLE)



1. INVERTING INPUT (A)

2. NONINVERTING INPUT (A)

8. NULL (B) 9. V+

3. NULL (A)

10. V<sub>O</sub> (B)

11. V+ 12. V<sub>O</sub> (A)

5. NULL (B) 6. NONINVERTING INPUT (B)

13. V+

7. INVERTING INPUT (B)

14. NULL (A)

ALL V+ PADS ARE INTERNALLY CONNECTED.

DIE SIZE  $0.110 \times 0.075$  inch, 8250 sq. mlls

 $(2.79 \times 1.91 \text{ mm}, 5.33 \text{ sq. mm})$ 

**WAFER TEST LIMITS** at  $V_8 = \pm 15$ V,  $T_A = 25$ °C for OP-215N, OP-215G and OP-215GR devices;  $T_A = 125$ °C for OP-215NT and OP-215GT devices, unless otherwise noted.

PARAMETER	SYMBOL	CONDITIONS	OP-215NT LIMIT	OP-215N LIMIT	OP-215GT LIMIT	OP-215G LIMIT	OP-215GR LIMIT	UNITS
Input Offset Voltage	Vos	$R_S = 50\Omega$	2	1	3	2	6	mV MAX
Input Bias Current	I <sub>B</sub>		±18	_	±18	_	_	nA MAX
Input Offset Current	los		14	<u> </u>	14		_	nA MAX
Large-Signal Voltage Gain	A <sub>VO</sub>	$V_O = \pm 10V$ , $R_L = 2k\Omega$	30	150	30	75	50	V/mV MIN
Input Voltage Range	IVR		±10.2	±10.2	±10.2	±10.2	±10.1	VMIN
Common-Mode Rejection Ratio	CMRR	V <sub>CM</sub> = ±IVR	82	86	82	86	82	dB MIN
Power Supply Rejection Ratio	PSRR	$V_S = \pm 10 \text{ to } \pm 16V$ $V_S = \pm 10 \text{ to } \pm 15V$	100	51 —	100	80 —	_ 100	μV/V MAX
Output Voltage Swing	v <sub>o</sub>	$R_L = 10k\Omega$ $R_L = 2k\Omega$	±12	±12 ±11	±12 —	±12 ±11	±12 ±11	V MIN
Supply Current	I <sub>SY</sub>			8.5	_	8.5	12.0	mA MAX

For 25°C characteristics of NT & GT devices, see N & G characteristics respectively.

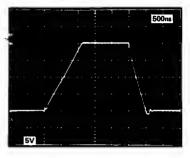
Electrical tests are performed at wafer probe to the limits shown. Due to variations in assembly methods and normal yield loss, yield after packaging is not guaranteed for standard product dice. Consult factory to negotiate specifications based on dice lot qualification through sample lot assembly and testing.

TYPICAL ELECTRICAL CHARACTERISTICS at  $V_S = \pm 15V$ ,  $T_A = +25^{\circ}$  C, unless otherwise noted.

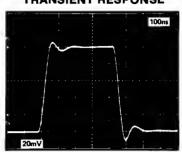
PARAMETER	SYMBOL	CONDITIONS	OP-215NT TYPICAL	OP-215N TYPICAL	OP-215GT TYPICAL	OP-215G TYPICAL	OP-215GR TYPICAL	UNITS
Average Input Offset Voltage Drift	TCVos	Unnulled R <sub>p</sub> = 100kΩ	2	2	3	3	4	μV/° C
Average Input Offset Voltage Drift	TCV <sub>OSn</sub>	Nulled R <sub>P</sub> = 100kΩ	0.5	0.5	1	1	2	μV/°C
Input Offset Current	los		3	3	3	3	3	pА
Input Bias Current	I <sub>B</sub>		± 15	± 15	± 15	±15	±15	рΑ
Slew Rate	SR	A <sub>VCL</sub> = +1	17	17	16	16	15	V/μs
Settling Time	t <sub>S</sub>	to 0.01% to 0.05% to 0.10%	2.2 1.1 0.9	2.2 1.1 0.9	2.3 1.1 0.9	2.3 1.1 0.9	2.4 1.2 1.0	μs
Gain Bandwidth Product	GBW		6.0	6.0	5.7	5.7	5.4	MHz
Closed-Loop Bandwidth	CLBW	A <sub>VCL</sub> = +1	14	14	13	13	12	MHz
Input Noise Voltage Density	e <sub>n</sub>	f <sub>O</sub> = 100Hz f <sub>O</sub> = 1000Hz	20 15	20 15	20 15	20 15	20 15	nV√Hz
Input Noise Current Density	in	f <sub>O</sub> = 100Hz f <sub>O</sub> = 1000Hz	0.01	0.01	0.01	0.01	0.01	p <b>A</b> /√ <del>Hz</del>
Input Capacitance	C <sub>IN</sub>		3	3	3	3	3	pF

# TYPICAL PERFORMANCE CHARACTERISTICS

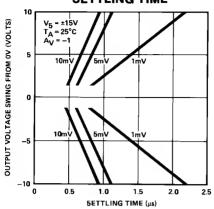
LARGE-SIGNAL TRANSIENT RESPONSE



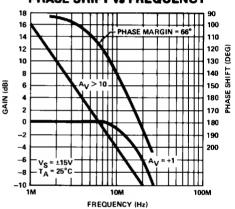
SMALL-SIGNAL TRANSIENT RESPONSE



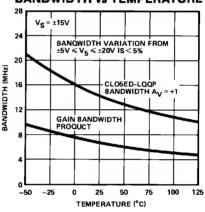
**SETTLING TIME** 



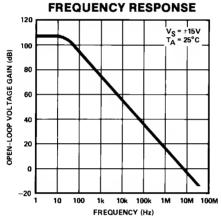
**CLOSED-LOOP BANDWIDTH AND** PHASE SHIFT VS FREQUENCY



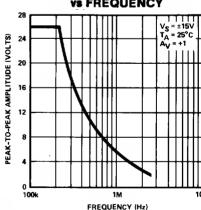
**BANDWIDTH vs TEMPERATURE** 



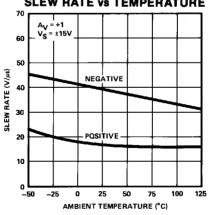
**OPEN-LOOP** 



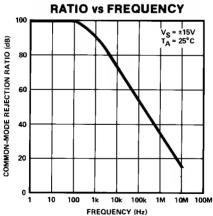
**MAXIMUM OUTPUT SWING VS FREQUENCY** 



SLEW RATE vs TEMPERATURE

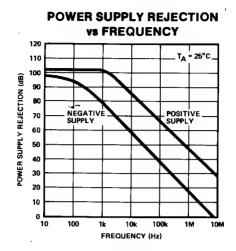


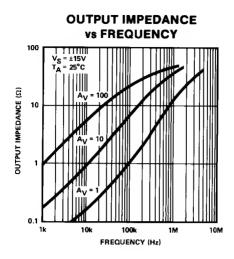
**COMMON-MODE REJECTION** 

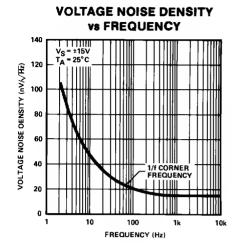


# **OP-215**

# **TYPICAL PERFORMANCE CHARACTERISTICS**

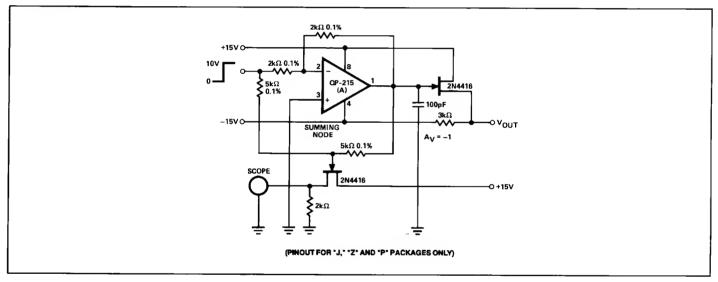




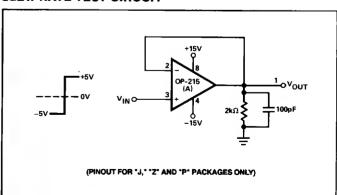


# **BASIC CONNECTIONS**

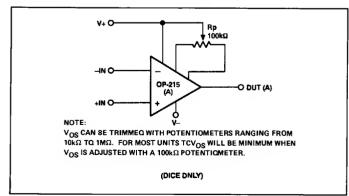
# SETTLING TIME TEST CIRCUIT



### **SLEW RATE TEST CIRCUIT**

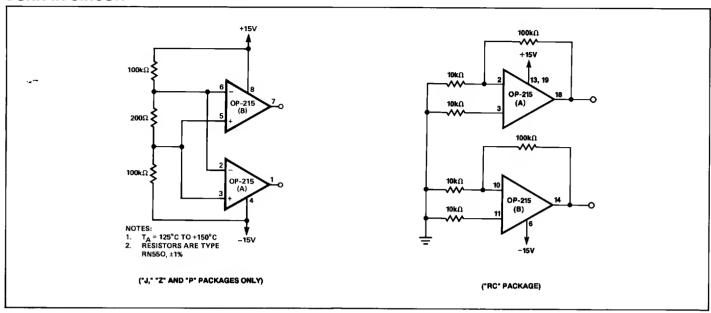


# INPUT OFFSET VOLTAGE NULLING



## **BASIC CONNECTIONS**

### **BURN-IN CIRCUIT**



### **APPLICATIONS INFORMATION**

# **DYNAMIC OPERATING CONSIDERATIONS**

As with most amplifiers, care should be taken with lead dress, component placement and supply decoupling in order to ensure stability. For example, resistors from the output to an input should be placed with the body close to the input to minimize "pick-up" and maximize the frequency of the feedback pole by minimizing the capacitance from the input to ground.

A feedback pole is created when the feedback around any amplifier is resistive. The parallel resistance and capacitance from the input of the device (usually the inverting input) to AC ground sets the frequency of the pole. In many instances, the frequency of this pole is much greater than the expected 3dB frequency of the closed-loop gain and consequently there is negligible effect on stability margin. However, if the feedback pole is less than approximately six times the expected 3dB frequency, a lead capacitor should be placed from the output to the negative input of the op amp. The value of the added capacitor should be such that the RC time constant of this capacitor and the resistance it parallels is greater than, or equal to, the original feedback-pole time constant.